Applicant(s)/Patent Under Application/Control No. Reexamination 09/837,480 NAKATA ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 Tracy Dove 1745 **U.S. PATENT DOCUMENTS** Date Document Number Classification Name Country Code-Number-Kind Code MM-YYYY Α US-US-В US-С US-D Ε US-US-F US-G US-Н 1 US-J US-US-Κ US-L US-Μ FOREIGN PATENT DOCUMENTS Document Number Date Classification Country Name MM-YY Country Code-Number-Kind Code Ν 0 Р Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) B.C. Cullity, Elements of X-Ray Diffraction, 2nd edition, pages 281-282. U 1978 (no month) ٧ W

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Х